

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/534,551	IGAWA ET AL.	
Examiner		Art Unit		Page 1 of 1
John S. Chu		1752		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,440,632 B2	08-2002	Yasuda, Tokugen	430/196
*	B	US-5,876,895 A	03-1999	Hishiro et al.	430/191
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 06035182 A	02-1994	Japan	HISHIRO et al.	---
	O	JP 06043637 A	02-1994	Japan	HISHIRO et al.	---
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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